



IFW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: **Shunsuke SHUTOU et al.**

Group Art Unit: **Not yet assigned**

Application Number: **10/579,467**

Examiner: **Not yet assigned**

Filed: **May 15, 2006**

Confirmation Number: **7024**

For: **RETARDATION FILM, METHOD FOR MANUFACTURING
RETARDATION FILM, METHOD FOR MANUFACTURING
LAMINATED RETARDATION FILM, OPTICAL FILM, AND
IMAGE DISPLAY APPARATUS**

Attorney Docket Number: **062096**

Customer Number: **38834**

INFORMATION DISCLOSURE STATEMENT
UNDER 37 C.F.R. §1.97(b)

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

August 15, 2006

Sir:

In compliance with 37 C.F.R. §1.56, Applicants direct the attention of the Patent and Trademark Office to the documents listed on the attached PTO/SB/08. This paper is being filed within the time periods set forth in 37 C.F.R. §1.97(b). A copy of each non-U.S. document is enclosed herewith.

If there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 50-2866.

Respectfully submitted,

WESTERMAN, HATTORI, DANIELS & ADRIAN, LLP


Stephen G. Adrian

Attorney for Applicants

Registration No. 32,878

Telephone: (202) 822-1100

Facsimile: (202) 822-1111

SGA/ya

Enclosures: PTO/SB/08
15 Document(s)



Combined Form PTO/SB/08A&B <u>INFORMATION DISCLOSURE</u> <u>STATEMENT BY APPLICANT</u> (use as many sheets as necessary)			<i>Complete if Known</i>		
			Application Number	10/579,467	
			Confirmation Number	7024	
			Filing Date	May 15, 2006	
			First Named Inventor	Shunsuke SHUTOU	
			Art Unit	Net yet assigned	
			Examiner Name	Not yet assigned	
Sheet	1	of	1	Attorney Docket Number	062096

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
		Number	Kind Code ² (if known)		
	1	US 5,344,916	A	09-06-1994	Harris et al.
	2	US 6,074,709	A	06-13-2000	Ezzell et al.
	3	US 6,132,147	A	07-21-1992	Takiguchi et al.
	4	US 2005/0030456	A1	02-10-2005	Murakami et al.
	5	US 6,215,539	B1	04-10-2001	Schadt et al.
	6	US 2005/0151906	A1	07-14-2005	Yoshimi et al.
	7	US 6,157,427	A	12-05-2000	Saynor et al.
		US			

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document			Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Translation ⁶
		Country Code ³	Number ⁴	Kind Code ⁵ (if known)			
	8	JP	2631015	B2	04-25-1997	Ricoh Co & Nippon Oil Co. Ltd.	Corrs. to 3
	9	JP	2000-511296	A	08-29-2000	Minnesota Mining and Manufacturing Co.	Corrs. to 10
	10	WO	97/44704	A1	11-27-1997	Minnesota Mining and Manufacturing Co.	N/A
	11	JP	8-511812	A	12-10-1996	The University of Akron	Corrs. to 12
	12	WO	94/24191	A1	10-27-1994	The University of Akron	N/A
	13	JP	2001-49110	A	02-20-2001	Nippon Shokubai Co., Ltd.	Abstract
	14	JP	10-508048	A	08-04-1998	The University of Akron	Corrs. to 15
	15	WO	96/11967	A1	04-25-1996	The University of Akron	N/A
	16	JP	2004-46065	A	02-12-2004	Nitto Denko Corp.	Corrs. to 4
	17	JP	2001-343529	A	12-14-2001	Kaneka Corporation	Corrs. to 18
	18	EP	1 160 591	A1	12-05-2001	Kaneka Corporation	N/A
	19	JP	9-222605	A	08-26-1997	Rolic Ag	Corrs. to 5
	20	WO	03/091767	A1	11-06-2003	Nitto Denko Corp.	Corrs. to 6
	21	JP	11-72621	A	03-16-1999	Sharp Corp.	Corrs. to 7

NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
	22	HA et al., "Spectroscopic Studies on the Liquid Crystal Alignment Mechanism for Polarized UV-exposed Organosoluble 6FDA-TFMB Polyimide Films", <i>Mol. Cryst. Liq. Cryst.</i> , Vol. 357, pp. 263-280, 2001	N/A

Examiner Signature	Date Considered
--------------------	-----------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to indicate here if English language Translation is attached.